

DMC3028LSD

30V COMPLEMENTARY DUAL ENHANCEMENT MODE MOSFET

Product Summary

Device	V _{(BR)DSS}	R _{DS(on)}	I _D T _A = 25°C			
01	30V	28mΩ @ V _{GS} = 10V 7.				
Q1	300	45mΩ @ V _{GS} = 4.5V	7.1A 5.6A			
02	201/	25mΩ @ V _{GS} = -10V	-7.4A			
Q2	-30V	41mΩ @ V _{GS} = -4.5V	-5.7A			

Description and Applications

This new generation complementary dual MOSFET features low onresistance and fast switching, making it ideal for high efficiency power management applications.

- Motor control
- Backlighting
- DC-DC Converters
- · Power management functions

Features and Benefits

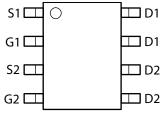
- · Low on-resistance
- · Fast switching speed
- "Green" Component and RoHS Compliant (Note 1)

Mechanical Data

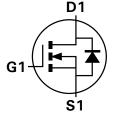
- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0 (Note 1)
- Moisture Sensitivity: Level 1 per J-STD-020D
- Terminals Connections: See Diagram
- Terminals: Finish Matte Tin annealed over Copper lead frame.
 Solderable per MIL-STD-202, Method 208
- Weight: 0.074 grams (approximate)



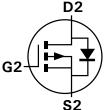




Top view



Q1 N-Channel



Q2 P-Channel

Ordering Information (Note 1)

Product	Marking	Reel size (inches)	Tape width (mm)	Quantity per reel
DMC3028LSD-13	C3028LD	13	12	2,500

Note:

1. Diodes, Inc. defines "Green" products as those which are Eu RoHS compliant and contain no halogens or antimony compounds; further information about Diodes Inc.'s "Green" Policy can be found on our website. For packaging details, go to our website

Marking Information



Oll = Manufacturer's Marking C3028LD = Product Type Marking Code YYWW = Date Code Marking YY = Year (ex: 09 = 2009) WW = Week (01-52)



Maximum Ratings @T_A = 25°C unless otherwise specified

	Characteristic		Symbol	N-Channel - Q1	P-Channel - Q2	Units
Drain-Source Voltage			V_{DSS}	30	-30	V
Gate-Source Voltage			V _{GSS}	±20	±20	V
Continuous Drain Current		(Notes 3 & 5)		7.1	-7.4	
	V _{GS} = 10V	T _A = 70°C (Notes 3 & 5)	Ι _D	5.7	-5.9	Α
		(Notes 2 & 5)		5.5	-5.8	A
		(Notes 2 & 6)		6.6	-6.8	
Pulsed Drain Current V _{GS} = 10V		(Notes 4 & 5)	I_{DM}	34	-36	Α
Continuous Source Current (Body diode) (Notes 3 & 5)		Is	3.5	-3.5	А	
Pulsed Source Current (Body diode) (Notes 4 & 5)		I _{SM}	34	-36	А	

Thermal Characteristics @T_A = 25°C unless otherwise specified

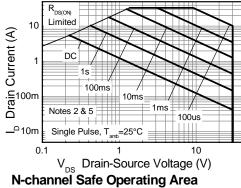
Characteristic		Symbol	N-Channel - Q1	P-Channel - Q2	Unit	
Power Dissipation Linear Derating Factor	(Notes 2 & 5)	PD	1 1	W mW/°C		
Power Dissipation Linear Derating Factor	(Notes 2 & 6)	P _D	1 1	W mW/°C		
Power Dissipation Linear Derating Factor	(Notes 3 & 5)	P _D	2	W mW/°C		
Thermal Resistance, Junction to Ambient	(Notes 2 & 5) (Notes 2 & 6) (Notes 3 & 5)	$R_{\theta JA}$	100 70 60		°C/W	
Thermal Resistance, Junction to Lead	(Notes 5 & 7)	$R_{\theta JL}$	51 46		°C/W	
Operating and Storage Temperature Range	T _{J,} T _{STG}	-55 to	°C			

Notes:

- 2. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.

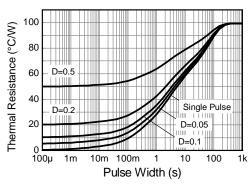
 3. Same as note (2), except the device is measured at t ≤ 10 sec.
- 4. Same as note (2), except the device is pulsed with D= 0.02 and pulse width $300 \, \mu s$. The pulse current is limited by the maximum junction temperature.
- 5. For a dual device with one active die.
- 6. For a device with two active die running at equal power.
- 7. Thermal resistance from junction to solder-point (at the end of the drain lead).

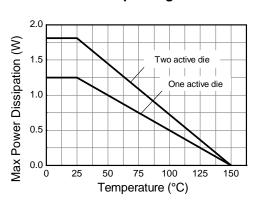




R_{DS(ON)} Limited Drain Current (A) Notes 2 & 5 Single Pulse, T_{ant}=25°C =

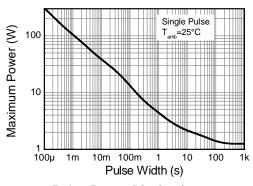
- V_{DS} Drain-Source Voltage (V) P-channel Safe Operating Area





Transient Thermal Impedance

Derating Curve



Pulse Power Dissipation





Electrical Characteristics – Q1 N-Channel @TA = 25°C unless otherwise specified

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	30	_	_	V	$I_D = 250 \mu A, V_{GS} = 0 V$
Zero Gate Voltage Drain Current	I _{DSS}	_	_	0.5	μА	V _{DS} = 30V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	V_{GS} = ±20V, V_{DS} = 0V
ON CHARACTERISTICS	,					
Gate Threshold Voltage	$V_{GS(th)}$	1.0		3.0	V	$I_D=250\mu A,\ V_{DS}=V_{GS}$
Static Drain-Source On-Resistance (Note 8)	R _{DS (ON)}	_		0.028	Ω	V _{GS} = 10V, I _D = 6.0A
Otalic Brain Gource on Nesistance (Note 6)	INDS (ON)			0.045	32	V _{GS} = 4.5V, I _D = 4.9A
Forward Transconductance (Notes 8 & 9)	g fs		12	_	S	V _{DS} = 15V, I _D = 6.0A
Diode Forward Voltage (Note 8)	V _{SD}		0.68	1.2	V	I _S = 1.7A, V _{GS} = 0V
Reverse recovery time (Note 9)	t _{rr}		11.5	_	ns	1 4 74 4:/44 4004/ -
Reverse recovery charge (Note 9)	Q _{rr}	_	4.4	_	nC	I _S = 1.7A, di/dt= 100A/μs
DYNAMIC CHARACTERISTICS (Note 9)					•	
Input Capacitance	C _{iss}	_	472	_	pF	
Output Capacitance	Coss	_	178	_	pF	V _{DS} = 15V, V _{GS} = 0V -f= 1MHz
Reverse Transfer Capacitance	C _{rss}	_	65	_	pF	1- 11011 12
Total Gate Charge	Qg	_	5.2	_	nC	V _{DS} = 15V, V _{GS} = 4.5V I _D = 6A
Total Gate Charge	Q_g	_	10.5	_	nC	
Gate-Source Charge	Q _{gs}	_	1.86	_	nC	V _{DS} = 15V, V _{GS} = 10V
Gate-Drain Charge	Q_{gd}	_	2.3	_	nC	-I _D = 6A
Turn-On Delay Time (Note 10)	t _{D(on)}	_	2.5	_	ns	
Turn-On Rise Time (Note 10)	t _r	_	3.1	_	ns	V _{DD} = 15V, V _{GS} = 10V
Turn-Off Delay Time (Note 10)	t _{D(off)}	_	14	_	ns	$I_D=1A, R_G \cong 6.0\Omega$
Turn-Off Fall Time (Note 10)	t _f		9.7		ns	<u> </u>

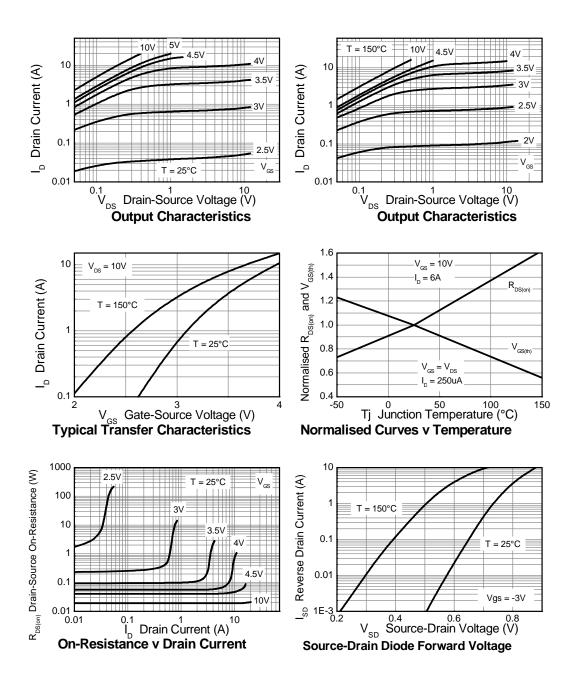
Notes:

- 8. Measured under pulsed conditions. Pulse width $\leq 300 \mu s;$ duty cycle $\leq 2\%$
- For design aid only, not subject to production testing.
 Switching characteristics are independent of operating junction temperatures.



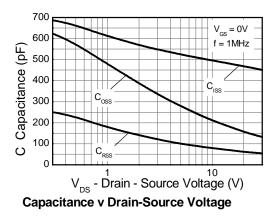


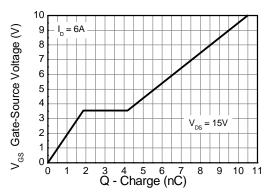
Q1 N-Channel





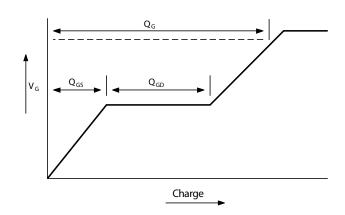
Q1 N-Channel continued

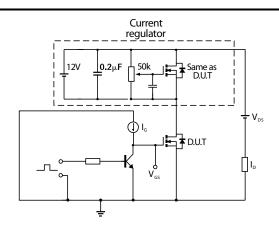




Gate-Source Voltage v Gate Charge

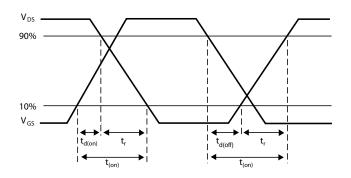
Test Circuits – Q1 N-Channel

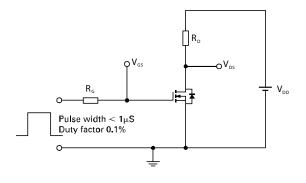




Basic gate charge waveform

Gate charge test circuit





Switching time waveforms

Switching time test circuit



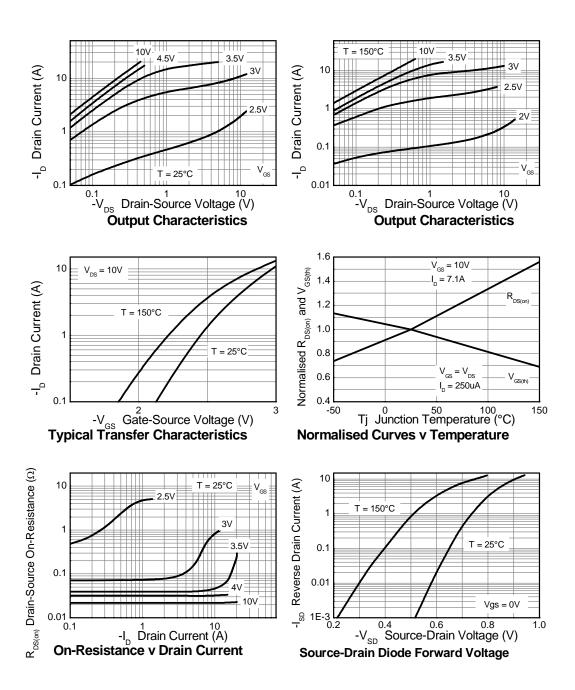
Electrical Characteristics – Q2 P-Channel @T_A = 25°C unless otherwise specified

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS					Į.	
Drain-Source Breakdown Voltage	BV _{DSS}	-30	_	_	V	$I_D = -250 \mu A, V_{GS} = 0 V$
Zero Gate Voltage Drain Current	I _{DSS}	_	_	-0.5	μΑ	V _{DS} = -30V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	V _{GS} = ±20V, V _{DS} = 0V
ON CHARACTERISTICS						
Gate Threshold Voltage	V _{GS(th)}	-1.0	_	-3.0	V	$I_D=-250\mu A,\ V_{DS}=V_{GS}$
Static Drain-Source On-Resistance (Note 8)	J			0.025	Ω	V _{GS} = -10V, I _D = -7.1A
Static Drain-Source On-Resistance (Note 8)	R _{DS (ON)}	_	_	0.041	12	V _{GS} = -4.5V, I _D = -5.5A
Forward Transconductance (Notes 8 & 9)	g fs	_	18.6	_	S	V _{DS} = -15V, I _D = -7.1A
Diode Forward Voltage (Note 8)	V_{SD}	_	-0.80	-1.2	V	I _S = -1.7A, V _{GS} = 0V
Reverse recovery time (Note 9)	t _{rr}		16.2		ns	
Reverse recovery charge (Note 9)	Q _{rr}	_	10	_	nC	I _S = -2.2A, di/dt= 100A/μs
DYNAMIC CHARACTERISTICS (Note 9)					•	
Input Capacitance	C _{iss}	_	1678	_	pF	
Output Capacitance	Coss	_	303		pF	V _{DS} = -15V, V _{GS} = 0V -f= 1MHz
Reverse Transfer Capacitance	C _{rss}	_	178		pF	TE TIVILIZ
Total Gate Charge	Qg	_	16.4	_	nC	V _{DS} = -15V, V _{GS} = -4.5V I _D = -7.1A
Total Gate Charge	Qg	_	31.6	_	nC	
Gate-Source Charge	Q _{gs}	_	4.3	_	nC	V _{DS} = -15V, V _{GS} = -10V
Gate-Drain Charge	Q _{gd}	_	6.2	_	nC	-I _D = -7.1A
Turn-On Delay Time (Note 10)	t _{D(on)}	_	3.5	_	ns	
Turn-On Rise Time (Note 10)	t _r	_	4.9	_	ns	V _{DD} = -15V, V _{GS} = -10V
Turn-Off Delay Time (Note 10)	t _{D(off)}	_	44	_	ns	I_{D} = -1A, $R_{G} \cong 6.0\Omega$
Turn-Off Fall Time (Note 10)	t _f	_	28	_	ns	

- 8. Measured under pulsed conditions. Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$
- For design aid only, not subject to production testing.
 Switching characteristics are independent of operating junction temperatures.

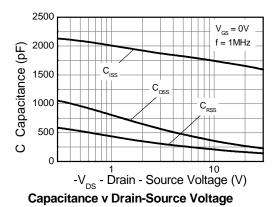


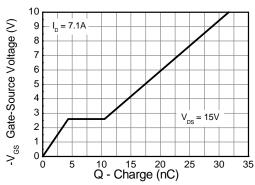
Q2 P-Channel





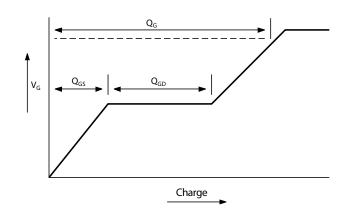
Q2 P-Channel continued





Gate-Source Voltage v Gate Charge

Test Circuits - Q2 P-Channel



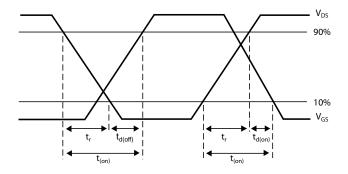
Current regulator

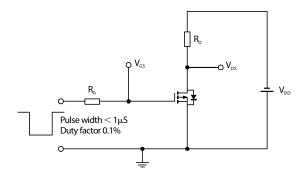
12V 0.2μF 50k D.U.T

V_{os}

Basic gate charge waveform

Gate charge test circuit



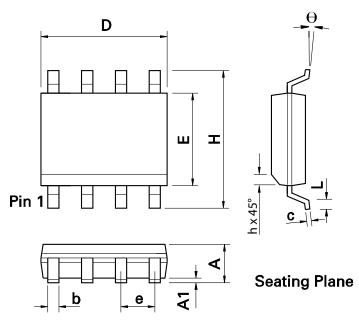


Switching time waveforms

Switching time test circuit

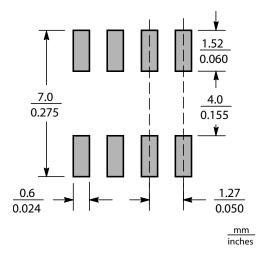


Package Outline Dimensions



DIM	Inches		Millimeters		DIM	Inches		Millimeters	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
Α	0.053	0.069	1.35	1.75	е	0.050 BSC		1.27 BSC	
A1	0.004	0.010	0.10	0.25	b	0.013 0.020		0.33	0.51
D	0.189	0.197	4.80	5.00	С	0.008	0.010	0.19	0.25
Н	0.228	0.244	5.80	6.20	θ	0°	8°	0°	8°
Е	0.150	0.157	3.80	4.00	h	0.010	0.020	0.25	0.50
L	0.016	0.050	0.40	1.27	-	-	-	-	-

Suggested Pad Layout







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